

<b>Notice of References Cited</b>	Application/Control No. 10/525,204		Applicant(s)/Patent Under Reexamination TAKEYAMA ET AL.	
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#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0022575	01-2003	Yoneda et al.	442/104
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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#### FOREIGN PATENT DOCUMENTS

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